

Correcting field-dependent aberrations in 3D localization microscopy with nanoscale accuracy

Single molecules can be localized to 10-40 nm *precision* in 3D, but systematic errors limit localization *accuracy* if not corrected. We show that field-dependent aberrations cause errors up to ~50-100 nm, which can be corrected by calibration.





Observed rate of change in z position ($\Delta z_{obs} / \Delta z_{cal}$) varies ~20% over field of view



This variation causes systematic *z*-dependent errors in 3D single-emitter localization that can be corrected by using local *z* calibrations from nanoholes



Alex von Diezmann, Maurice Lee, Matt Lew, and W. E. Moerner, Optica 2 (11), 985